



HI-304/883

T-51-11

January 1989

Dual SPST CMOS Analog Switch

Features

- This Circuit is Processed in Accordance with MIL-Std-883 and is Fully Conformant Under the Provisions of Paragraph 1.2.1.
- Analog Signal Range ($\pm 15V$ Supplies)..... $\pm 15V$
- Low Leakage ($+25^{\circ}C$)..... $1nA$ (Max)
- Low Leakage ($+125^{\circ}C$)..... $100nA$ (Max)
- Low ON Resistance..... 50Ω (Max)
- Charge Injection..... $30pC$ (Typ)
- CMOS Compatible
- Symmetrical Switch Elements
- Low Operating Power
- Compatible with DG304

Applications

- Sample and Hold, i.e. Low Leakage Switching
- Op Amp Gain Switching, i.e. Low ON Resistance
- Portable, Battery Operated Circuits
- Low Level Switching Circuits
- Dual or Single Supply Systems

Description

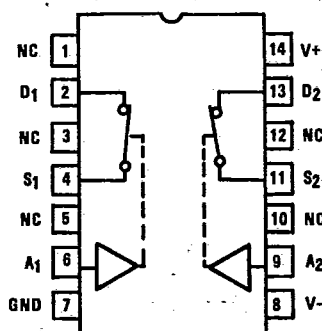
The HI-304/883 switch is a monolithic device fabricated using CMOS technology and the Harris Dielectric Isolation process. This switch features low and nearly constant ON resistance over the full analog signal range, and low power dissipation.

The HI-304/883 is CMOS compatible and has a logic "0" condition with an input less than 3.5V and a logic "1" condition with an input greater than 11V.

The HI-304/883 is pin-for-pin compatible with the industry standard Siliconix DG304. The device is available in a 14 pin Ceramic DIP and in a 10 pin Metal Can. The HI-304/883 operates over the $-55^{\circ}C$ to $+125^{\circ}C$ temperature range.

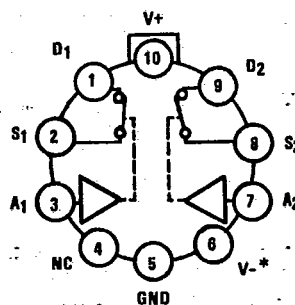
Pinouts

HI1-304/883 (CERAMIC DIP)
TOP VIEW



LOGIC	SWITCH
0	OFF
1	ON

HI2-304/883 (METAL CAN)
TOP VIEW



*The substrate and case are internally tied to V-. (The case should not be used as the V- connection, however.)

Absolute Maximum Ratings

Voltage Between V+ and V- Terminals	44V
$\pm V_{SUPPLY}$ to Ground (V+, V-)	$\pm 22V$
Analog Input Voltage +V _S	+V _{SUPPLY} +1.5V
-V _S	-V _{SUPPLY} -1.5V
Digital Input Voltage +V _A	+V _{SUPPLY} +4V
-V _A	-V _{SUPPLY} -4V
Peak Current (S or D) (Pulse at 1ms, 10% Duty Cycle Max)	40mA
Continuous Current	30mA
Junction Temperature	+175°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (Soldering 10 sec)	$\leq 275^\circ C$

Thermal Information

Thermal Resistance	θ_{JA}	θ_{JC}
Ceramic DIP Package	98°C/W	30°C/W
Metal Can Package	117°C/W	35°C/W
Package Power Dissipation at +75°C		
Ceramic DIP Package	0.77W	
Metal Can Package	0.84W	
Package Power Dissipation Derating Factor Above +75°C		
Ceramic DIP Package	10.32mW/°C	
Metal Can Package	8.56mW/°C	

CAUTION: Absolute maximum ratings are limiting values, applied individually, beyond which the serviceability of the circuit may be impaired. Functional operability under any of these conditions is not necessarily implied.

Recommended Operating Conditions

Operating Temperature Range	-55°C to +125°C
Operating Supply Voltage ($\pm V_{SUPPLY}$)	$\pm 15V$
Analog Input Voltage (V _S)	$\pm V_{SUPPLY}$

Logic Low Level (V _{AL})	0V to 3.5V
Logic High Level (V _{AH})	11V to +V _{SUPPLY}

TABLE 1. D.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Tested at: +V_{SUPPLY} = +15V, -V_{SUPPLY} = -15V, GND = 0V, Unless Otherwise Specified

D.C. PARAMETERS	SYMBOL	CONDITIONS	GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Switch "ON" Resistance	R _{DS}	V _A = 11V, V _D = 10V, I _S = -10mA S1/S2	1	+25°C	-	50	Ω
			2,3	-55°C to +125°C	-	75	Ω
		V _A = 11V, V _D = -10V, I _S = 10mA S1/S2	1	+25°C	-	50	Ω
			2,3	-55°C to +125°C	-	75	Ω
Source "OFF" Leakage Current	I _{S(OFF)}	V _S = +14V, V _D = -14V, V _A = 3.5V S1/S2	1	+25°C	-1	1	nA
			2,3	-55°C to +125°C	-100	100	nA
		V _S = -14V, V _D = +14V, V _A = 3.5V S1/S2	1	+25°C	-1	1	nA
			2,3	-55°C to +125°C	-100	100	nA
Drain "OFF" Leakage Current	I _{D(OFF)}	V _S = +14V, V _D = -14V, V _A = 3.5V S1/S2	1	+25°C	-1	1	nA
			2,3	-55°C to +125°C	-100	100	nA
		V _S = -14V, V _D = +14V, V _A = 3.5V S1/S2	1	+25°C	-1	1	nA
			2,3	-55°C to +125°C	-100	100	nA
Channel "ON" Leakage Current	I _{D(ON)}	V _D = V _S = +14V, V _A = 11V S1/S2	1	+25°C	-1	1	nA
			2,3	-55°C to +125°C	-100	100	nA
		V _D = V _S = -14V, V _A = 11V S1/S2	1	+25°C	-1	1	nA
			2,3	-55°C to +125°C	-100	100	nA
Low Level Input Current	I _{AL}	V _A = 3.5V	1	+25°C	-1.0	1.0	μA
			2,3	-55°C to +125°C	-1.0	1.0	μA
High Level Input Current	I _{AH}	V _A = 11V	1	+25°C	-1.0	1.0	μA
			2,3	-55°C to +125°C	-1.0	1.0	μA
Supply Current	+I _{CC}	V _{A1} = V _{A2} = 0V	1	+25°C	-	10	μA
			2,3	-55°C to +125°C	-	100	μA
		V _{A1} = V _{A2} = 15V	1	+25°C	-	10	μA
			2,3	-55°C to +125°C	-	100	μA
Supply Current	-I _{CC}	V _{A1} = V _{A2} = 0V	1	+25°C	-10	-	μA
			2,3	-55°C to +125°C	-100	-	μA
		V _{A1} = V _{A2} = 15V	1	+25°C	-10	-	μA
			2,3	-55°C to +125°C	-100	-	μA

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CAUTION: These devices are sensitive to electrostatic discharge. Proper I.C. handling procedures should be followed.

TABLE 2. A.C. ELECTRICAL PERFORMANCE CHARACTERISTICS

Device Tested at: +VSUPPLY = +15V, -VSUPPLY = -15V, GND = 0V, Unless Otherwise Specified

PARAMETERS	SYMBOL	CONDITIONS	GROUP A-SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Turn "ON" Time	t_{ON}	$C_L = 33\text{pF}$ $R_L = 300\Omega$	9	+25°C	-	250	ns
			10, 11	-55°C, +125°C	-	500	ns
Turn "OFF" Time	t_{OFF}	$C_L = 33\text{pF}$ $R_L = 300\Omega$	9	+25°C	-	150	ns
			10, 11	-55°C, +125°C	-	450	ns

TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS (NOTE 1)

Device Characterized at: +VSUPPLY = +15V, -VSUPPLY = -15V, GND = 0V, Unless Otherwise Specified

PARAMETERS	SYMBOL	CONDITIONS	NOTE	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Switch Input Capacitance	$C_{IS(OFF)}$	Measured Source to GND	1	+25°C	-	28	pF
Driver Input Capacitance	C_{C1}	$V_A = 0V$	1	+25°C	-	10	pF
	C_{C2}	$V_A = 15V$	1	+25°C	-	10	pF
Switch Output Capacitance	C_{OS}	Measured Drain to GND	1	+25°C	-	28	pF
Off Isolation	V_{ISO}	$f = 1\text{MHz}$, $V_{GEN} = 1V_{p-p}$	1	+25°C	40	-	dB
Crosstalk	V_{CT}	$f = 1\text{MHz}$, $V_{GEN} = 1V_{p-p}$	1	+25°C	40	-	dB
Charge Transfer	V_{CTE}	$V_S = \text{GND}$, $C_L = 0.01\mu\text{F}$	1	+25°C	-	15	mV

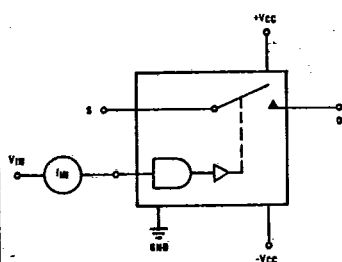
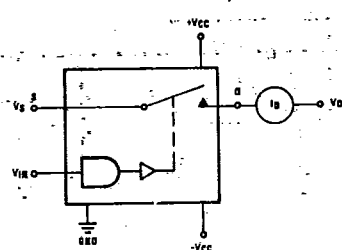
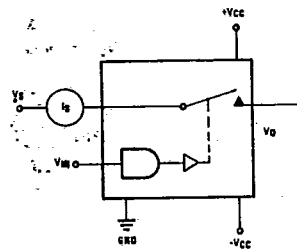
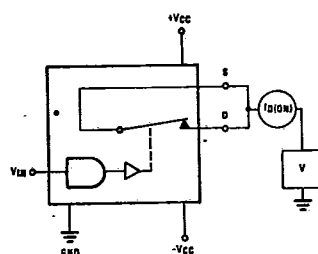
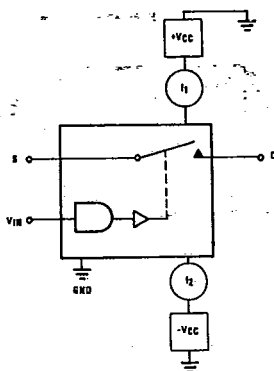
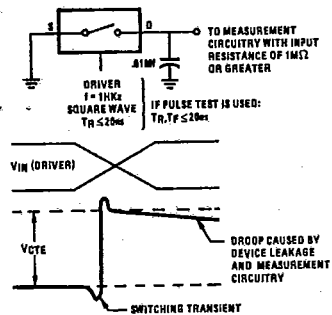
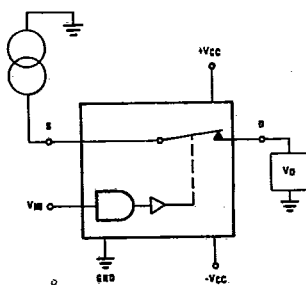
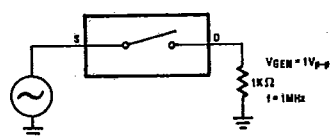
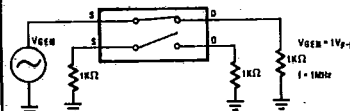
NOTE 1. Parameters listed in Table 3 are controlled via design or process parameters and are not directly tested at final production. These parameters are lab characterized upon initial design release, or upon design changes. These parameters are guaranteed by characterization based upon data from multiple production runs which reflect lot to lot and within lot variation.

TABLE 4. ELECTRICAL TEST REQUIREMENTS

MIL-STD-883 TEST REQUIREMENTS	SUBGROUPS (SEE TABLES 1 & 2)
Interim Electrical Parameters (Pre Burn-In)	1
Final Electrical Test Parameters	1*, 2, 3, 9, 10, 11
Group A Test Requirements	1, 2, 3, 9, 10, 11
Groups C & D Endpoints	1

* PDA applies to Subgroup 1 only.

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Test Circuits**INPUT LEAKAGE CURRENT****I_D(OFF)****I_S(OFF)****I_D(ON)****SUPPLY CURRENTS****CHARGE TRANSFER ERROR**NOTE: V_{CTE} may be a positive or negative value**R_{DS}****OFF CHANNEL ISOLATION****CROSSTALK BETWEEN CHANNELS**

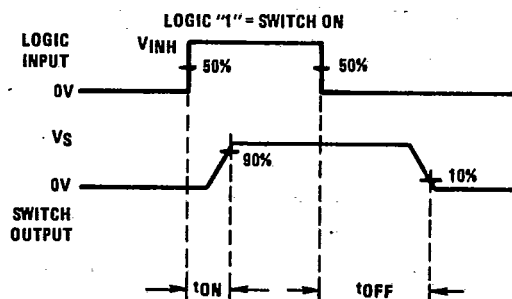
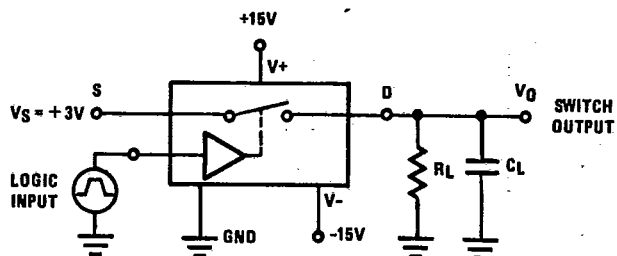
For Detail Information Refer to HI-304/883 Test Tech Brief

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Test Waveforms

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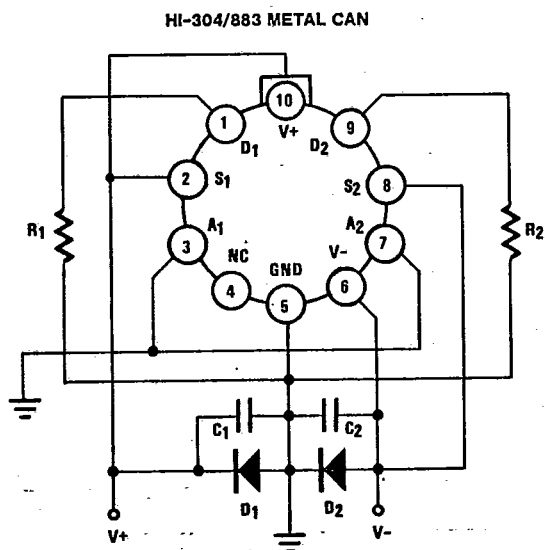
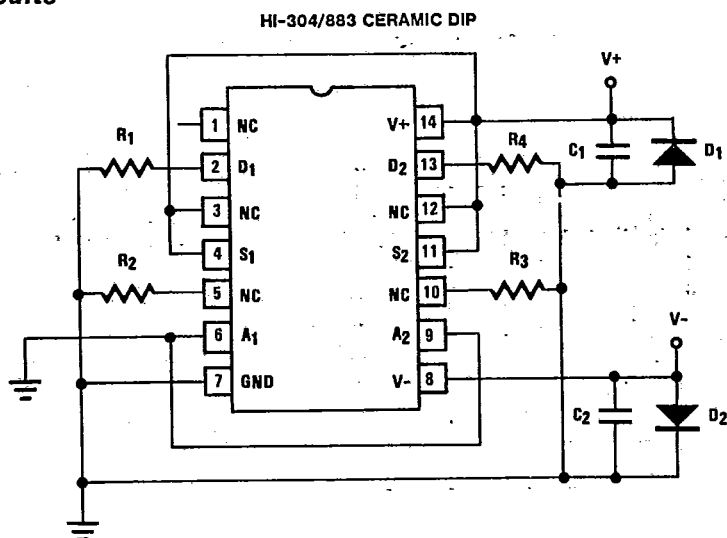


NOTES:

1. $R_L = 300\Omega$; $C_L = 33pF$
 2. $V_{INH} = 15V$
- RISETIME (1.5V to 13.5V) $\leq 20ns$
 FALLTIME (13.5V to 1.5V) $\leq 20ns$

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Burn-In Circuits



NOTES:

$R_1 = R_2 = R_3 = R_4 = 10K\Omega, \pm 5\%$ (per socket)
 $C_1 = C_2 = 0.01\mu F$ (per socket) or $0.1\mu F$ (per row)
 $D_1 = D_2 = IN4002$ or Equivalent/Board
 $|V^+ - V^-| = 30V$

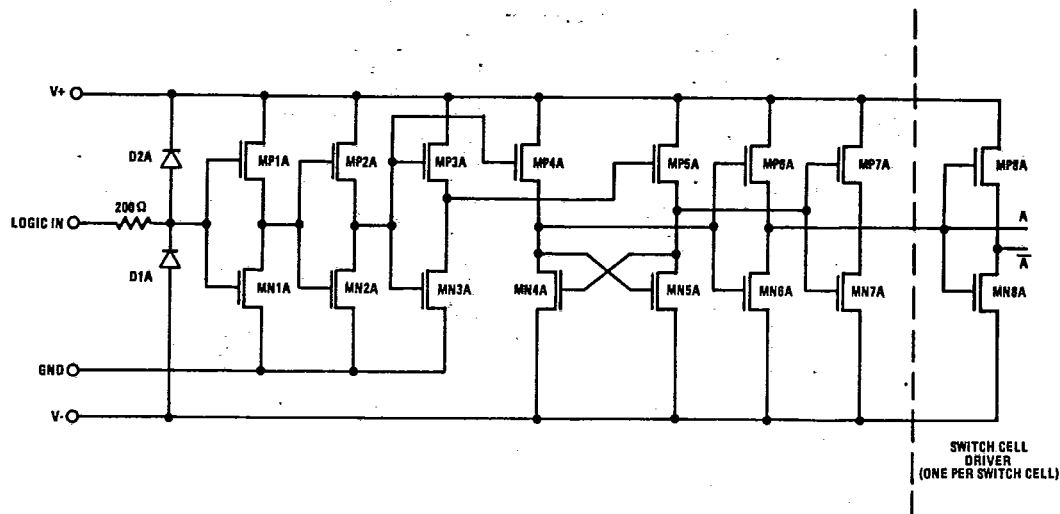
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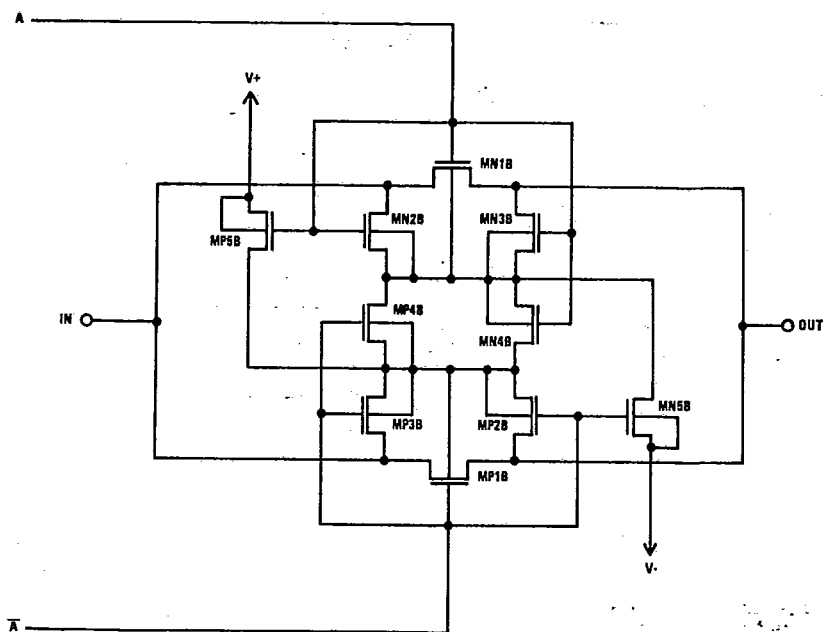
Schematic Diagram

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DIGITAL INPUT BUFFER AND LEVEL SHIFTER



SWITCH CELL



Die Characteristics**DIE DIMENSIONS:**

76 x 60.6 x 19 mils

METALLIZATION:

Type: Aluminum

Thickness: $16k\text{\AA} \pm 2k\text{\AA}$ **GLASSIVATION:**

Type: Nitride

Thickness: $7k\text{\AA} \pm 0.7k\text{\AA}$ **DIE ATTACH:**

Material: Gold/Silicon Eutectic Alloy

Temperature: Ceramic DIP — 460°C (Max)

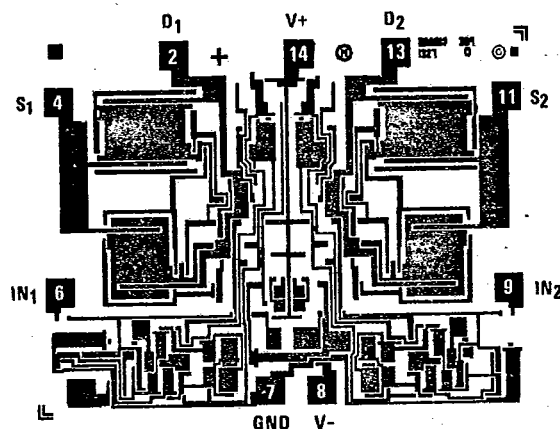
Metal Can — 420°C (Max)

WORST CASE CURRENT DENSITY: $3.9 \times 10^5 \text{A/cm}^2$ at 30mA

This device meets Glassivation Integrity Test
requirement per Mil-Std-883 Method 2021 and
Mil-M-38510 paragraph 3.5.5.4.

Metallization Mask Layout

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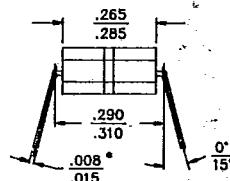
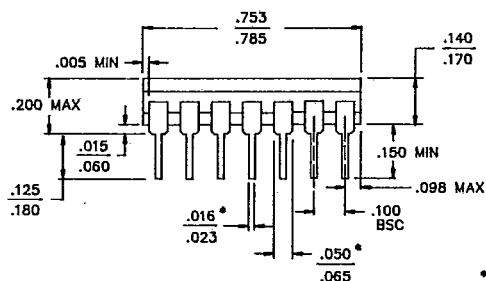
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Packaging†

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14 PIN CERAMIC DIP



* INCREASE MAX LIMIT BY .003 INCHES
MEASURED AT CENTER OF FLAT FOR
SOLDER FINISH

LEAD MATERIAL: Type B

LEAD FINISH: Type A

PACKAGE MATERIAL: Ceramic, 90% Alumina

PACKAGE SEAL:

Material: Glass Frit

Temperature: 450°C ± 10°C

Method: Furnace Seal

INTERNAL LEAD WIRE:

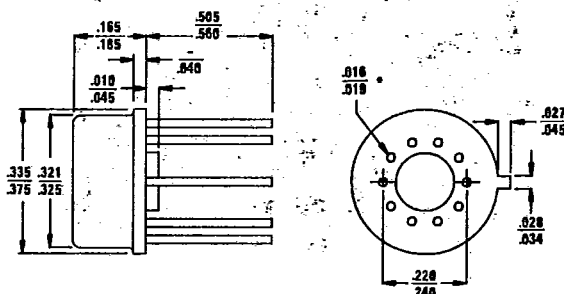
Material: Aluminum

Diameter: 1.25 Mil

Bonding Method: Ultrasonic

COMPLIANT OUTLINE: 38510 D-1

10 PIN METAL CAN



* Maximum Limits are Increased by 0.003 inches for Solder Dip Finish.

LEAD MATERIAL: Type A

LEAD FINISH: Type C

PACKAGE MATERIAL: Kovar Header with Nickel Can

PACKAGE SEAL:

Material: No Seal Material

Temperature: Room Temperature

Method: Resistance Weld

INTERNAL LEAD WIRE:

Material: Aluminum

Diameter: 1.25 Mil

Bonding Method: Ultrasonic

COMPLIANT OUTLINE: 38510 A-2

NOTE: All Dimensions are $\frac{\text{Min}}{\text{Max}}$, Dimensions are in inches.

†Mil-M-38510 Compliant Materials, Finishes, and Dimensions.



DESIGN INFORMATION

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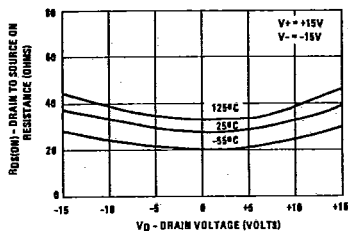
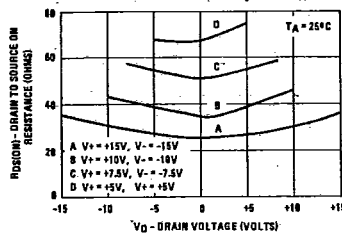
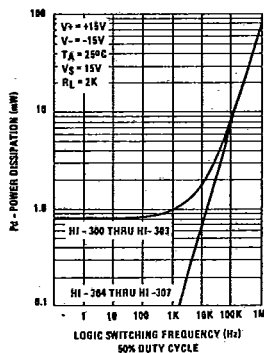
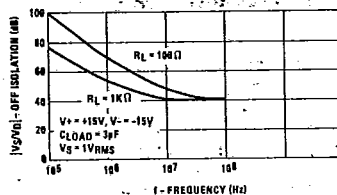
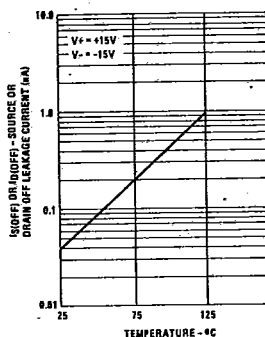
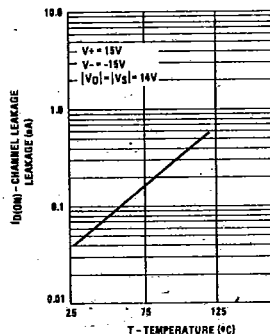
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Dual SPST CMOS Analog Switch

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Typical Performance Characteristics Unless Otherwise Specified: $V_+ = +15V$, $V_- = -15V$, $T_A = +25^\circ C$

 $R_{DS(ON)}$ vs. V_D AND TEMPERATURE **$R_{DS(ON)}$ vs. V_D AND POWER SUPPLY VOLTAGE****DEVICE POWER DISSIPATION vs. SWITCHING FREQUENCY SIGNAL LOGIC INPUT****OFF ISOLATION vs. FREQUENCY** **$I_S(OFF)$ or $I_D(OFF)$ vs. TEMPERATURE*** **$I_D(OFF)$ vs. TEMPERATURE***

* The net leakage into the source or drain is the N-channel leakage minus the P-channel leakage. This difference can be positive, negative, or zero depending on the analog voltage and temperature, and will vary greatly from unit to unit.

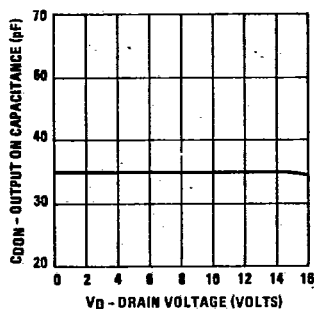
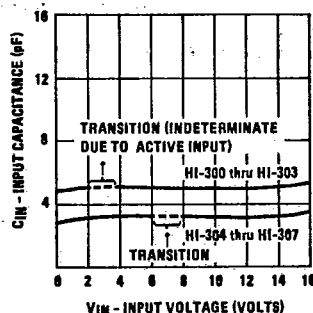
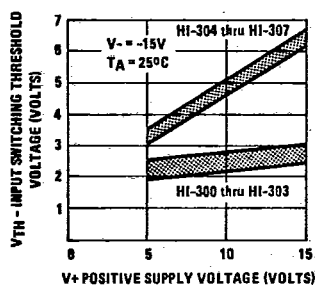
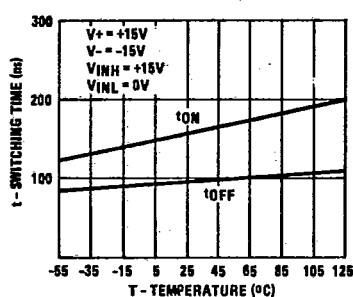
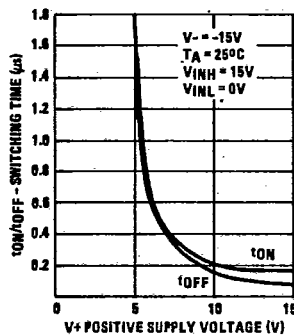
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CMOS ANALOG SWITCHES

DESIGN INFORMATION (Continued)

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Typical Performance Characteristics Unless Otherwise Specified: $V^+ = +15V$, $V^- = -15V$, $T_A = +25^\circ C$

OUTPUT ON CAPACITANCE vs. DRAIN VOLTAGE**DIGITAL INPUT CAPACITANCE vs. INPUT VOLTAGE****INPUT SWITCHING THRESHOLD vs. POSITIVE SUPPLY VOLTAGE****SWITCHING TIME vs. TEMPERATURE****SWITCHING TIME vs. POSITIVE SUPPLY VOLTAGE****SWITCHING TIME vs. NEGATIVE SUPPLY VOLTAGE**